

EL896635818US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Yuan-Ku LAN )  
Serial No.: Not yet assigned )  
Filed: Concurrently herewith ) Our Ref: B-4514 619559-4  
For: "METHOD OF CHECKING OVERLAP )  
ACCURACY OF PATTERNS ON FOUR )  
STACKED SEMICONDUCTOR LAYERS" ) Date: February 28, 2002



CLAIM TO PRIORITY UNDER 35 U.S.C. 119

Commissioner of Patents and Trademarks  
Box New Patent Application  
Washington, D.C. 20231

Sir:

[X] Applicant hereby makes a right of priority claim under 35  
U.S.C. 119 for the benefit of the filing date(s) of the  
following corresponding foreign application(s):

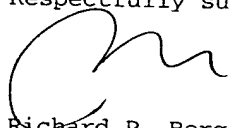
<u>COUNTRY</u>	<u>FILING DATE</u>	<u>SERIAL NUMBER</u>
Taiwan, R.O.C.	4 September 2001	90121880

[ ] A certified copy of each of the above-noted patent  
application was filed with the Parent Application  
No. \_\_\_\_\_.

[ ] To support applicants' claim, a certified copy of the above-  
identified foreign patent application is enclosed herewith.

[X] The priority document will be forwarded to the Patent Office  
when required or prior to issuance.

Respectfully submitted,

  
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